

Search Notes

Application/Control No.

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Examiner

Len Tran

Applicant(s)/Patent under
Reexamination

DEIBL ET AL.

Art Unit

1725

SEARCHED

Class	Subclass	Date	Examiner
164	448, 442, 427	3/17/2007	LT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Double Patenting search	3/17/2007	LT